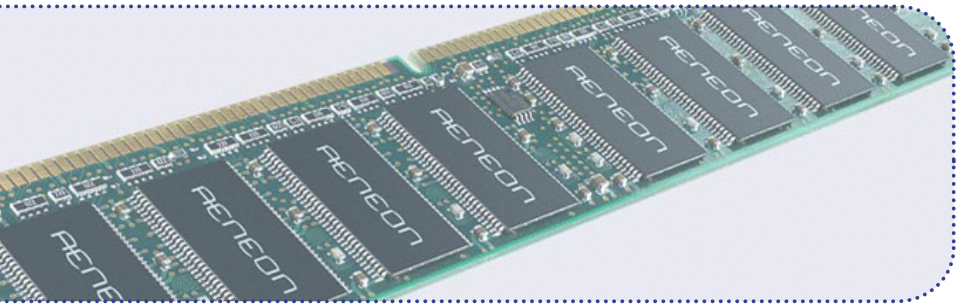

AENEON
Simply advanced

Unbuffered Memory Module
Data Sheet

# AET760UD00-25D

1 GByte DDR2–800 CL5 240-Pin UDIMM

## Description

This data sheet describes features and specification of AENEON™ memory module family AET760UD00-25D. The four digit product type postfix is for internal logistic purposes.

## Features

- 1 GByte organized as 128 M x 64 bit
- Double Data Rate Two SDRAM components
- Speed grade DDR2–800 CL5 on component level
- Provides up to 6400 MByte per second on module level
- Module Code PC2–6400U–555–12
- 240-Pin Dual Inline Memory Module (DIMM) with gold contacts
- Fitting in industry standard motherboards

## Specification

| Parameter | Values |
|---|---|
| Clock cycle time $t_{CK}$ for CL4 | 3.75 ns (min.) / 8 ns (max.) |
| Clock cycle time $t_{CK}$ for CL5 | 2.5 ns (min.) / 8 ns (max.) |
| Row cycle time $t_{RC}$ | 57.5 ns (min.) |
| Refresh row cycle time $t_{RFC}$ | 105 ns (min.) |
| Activate to read/write delay $t_{RCD}$ | 12.5 ns (min.) |
| Row active time $t_{RAS}$ | 45 ns (min.) / 70.000 ns (max.) |
| Single power supply $V_{DD}$ = $V_{DDQ}$ | 1.8 V ± 0.1 V |
| Operating power $I_{DD0}$ | 1.6 W (max.) |
| Module dimensions L x W x H | 133.35 mm x 30.0 mm x 4.0 mm (max.) |
| | 5.25" x 1.18" x 0.16" (max.) |

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1. A failure of the AENEON Products can reasonable be expected to –directly or indirectly–
   a. Have a detrimental effect on such Critical Systems in terms of reliability, effectiveness or safety; or
   b. Cause the failure of such Critical Systems; or
2. A failure or malfunction of such Critical Systems can reasonably be expected to –directly or indirectly–
   a. Endanger the health or the life of the user of such Critical Systems or any other person; or
   b. Otherwise cause material damages (including but not limited to damages or serious injury to life or property, whether tangible or intangible).